PCN Number: 2014		1007001A		PC	N Date:	2/19/2015			
Title: Die Conversion for select AUP LL Devices in DBV, DCK and DRL Packages									
Customer Contact: PCN Manager Dept: Quality Services									
Propose	d 1 st Ship Dat			/09/2015	Estim	Estimated Sample Availability:			Date provided at sample request.
Change [*]	Гуре:							-	
Assembly Site			Assembly P				Assembly Materials		
Desi				Electrical Sp				Mechanical Specification	
Test			Packing/Shipping/Labeling			Test Pro			
	r Bump Site		Wafer Bump Material				Bump Process		
	r Fab Site		Wafer Fab Materials			Wafer Fab Process			
				Part number change PCN Details					
Descript	ion of Change			PCN	Deta	115			
Revision striketh remain or	Description of Change: Revision A is to announce the <u>retraction</u> of select devices. Retracted devices are identified with a strikethrough and are highlighted in yellow in the Product Affected Section. These devices will remain on the current Die Revision.								
Revision	This change notification is to announce a Die Conversion for select AUP LL Devices. The Die Revision will change from X/A to C. Devices affected by this change are listed in the product affected section of this notification. There will be no change to the data sheet.								
Reason	or Change:								
	Continuity of Supply								
Anticipa	ted impact or	Fit, I	orn	n, Function,	Qualit	y or Reliabili	ty (positive	/ negative):
	Reliability & electrical characterization evaluation showed no adverse impacts.								
Changes	Changes to product identification resulting from this PCN:								
Die Rev	designator w	ill cha	nge	as shown i	n table	e & sample la	bel	below:	
Current New Die Rev [2P] Die Rev [2P] X/A C Sample product shipping label to indicate die rev location (not actual product label) INSTRUMENTS GA ZDC: ZOC / 1 YEAR SEAL DT MSL 2 / 2600C / 1 YEAR SEAL DT GA MSL 2 / 2600C / 1 YEAR SEAL DT GA OPT: JIE / 235C / UNLIM 03/29 / 04 ITEM: 39 LBL: 5A LBL: 5A C) TO : 1750									
New = C									

Product Affected:			
SN74AUP1G00DBVR	SN74AUP1G08DBVR	SN74AUP1G240DBVR	SN74AUP1G58DCKT
SN74AUP1G00DBVT	SN74AUP1G08DBVT	SN74AUP1G240DBVT	SN74AUP1G58DRLR
SN74AUP1G00DCKT	SN74AUP1G08DCKT	SN74AUP1G240DCKT	SN74AUP1G79DBVR
SN74AUP1G00DRLR	SN74AUP1G08DRLR	SN74AUP1G32DBVR	SN74AUP1G79DBVT
SN74AUP1G02DBVR	SN74AUP1G125DBVR	SN74AUP1G32DBVT	SN74AUP1G79DCKT
SN74AUP1G02DBVT	SN74AUP1G125DBVT	SN74AUP1G32DCKT	SN74AUP1G79DRLR
SN74AUP1G02DCKT	SN74AUP1G125DCKT	SN74AUP1G32DRLR	SN74AUP1G80DBVR
SN74AUP1G02DRLR	SN74AUP1G125DRLR	SN74AUP1G34DBVR	SN74AUP1G80DBVT
SN74AUP1G04DBVR	SN74AUP1G126DBVR	SN74AUP1G34DBVT	SN74AUP1G80DCKT
SN74AUP1G04DBVT	SN74AUP1G126DBVT	SN74AUP1G34DCKT	SN74AUP1G97DBVR
SN74AUP1G04DCKT	SN74AUP1G126DCKT	SN74AUP1G34DRLR	SN74AUP1G97DBVT
SN74AUP1G04DRLR	SN74AUP1G126DRLR	SN74AUP1G57DBVR	SN74AUP1G97DCKR
SN74AUP1G06DBVR	SN74AUP1G14DBVR	SN74AUP1G57DBVT	SN74AUP1G97DCKT
SN74AUP1G06DBVT	SN74AUP1G14DBVT	SN74AUP1G57DCKR	SN74AUP1G97DRLR
SN74AUP1G06DCKT	SN74AUP1G14DCKT	SN74AUP1G57DCKT	SN74AUP1G98DBVR
SN74AUP1G06DRLR	SN74AUP1G14DRLR	SN74AUP1G57DRLR	SN74AUP1G98DBVT
SN74AUP1G07DBVR	SN74AUP1G17DBVR	SN74AUP1G57DRLR-P	SN74AUP1G98DCKR
SN74AUP1G07DBVT	SN74AUP1G17DBVT	SN74AUP1G58DBVR	SN74AUP1G98DCKT
SN74AUP1G07DCKT	SN74AUP1G17DCKT	SN74AUP1G58DBVT	SN74AUP1G98DRLR
SN74AUP1G07DRLR	SN74AUP1G17DRLR	SN74AUP1G58DCKR	

Reference Qualification Data: (Approved 11/29/2010) This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qualification Device Construction Details:						
Qualification Vehicle #1: SN74AUP1G00DCKR						
Wafer Fab Site	FREISING Wafer Process		P9722			
Protective Die Coating	10KACN					
Qualification: Pla	Qualification: 🗌 Plan 🛛 Test Results					
Reliability Test	Conditions		Sample Size (PASS/FAIL)			
Electrical Char	Approved by Product Engineer		PASS			
ESD (CDM)	1500 V		3/0			
Manufacturability	Wafer Fab (per mfg. Site specification)		PASS			
Manufacturability-TQ	Assembly (per mfg. Site specification)		PASS			
Notes: Qualification tests "pass" on zero fails for each test						
Qualification Vehicle #2: SN74AUP1G02DCKR						
Wafer Fab Site	FREISING	Wafer Process:	P9722			
Protective Die Coating	: 10KACN					

Qualification: 🗌 Pla	n 🛛 Test Results				
Reliability Test	Conditions		Sample Size (PASS/FAIL)		
Electrical Char	Approved by Product Engineer		PASS		
ESD (CDM)	1500 V		3/0		
Manufacturability	Wafer Fab (per mfg. Site specif	fication)	PASS		
Manufacturability-TQ	Assembly (per mfg. Site specifi	cation)	PASS		
	ion tests "pass" on zero fails for				
Qualification Vehicle #3: SN74AUP1G04DCKR					
Wafer Fab Site	e: FREISING Wafer Process:		P9722		
Protective Die Coating	g: 10KACN				
Qualification: 🗌 Pla	n 🛛 Test Results				
Reliability Test	Conditions		Sample Size (PASS/FAIL)		
Electrical Char	Approved by Product Engineer		PASS		
ESD (CDM)	1500 V		3/0		
Manufacturability	Wafer Fab (per mfg. Site specification)		PASS		
Manufacturability-TQ	Assembly (per mfg. Site specification)		PASS		
Notes: Qualification tests "pass" on zero fails for each test					
(Qualification Vehicle #4: SN74	UP1G06DCKR			
Wafer Fab Site	: FREISING	Wafer Process:	P9722		
Protective Die Coating	: 10KACN				
Qualification: 🗌 Plan 🛛 Test Results					
Reliability Test	Conditions		Sample Size (PASS/FAIL)		
Electrical Char	Approved by Product Engineer		PASS		
ESD (CDM)	1500 V		3/0		
Manufacturability	Wafer Fab (per mfg. Site specification)		PASS		
Manufacturability-TQ	Assembly (per mfg. Site specification)		PASS		
Notes: Qualification tests "pass" on zero fails for each test					
Qualification Vehicle #5: SN74AUP1G07DCKR					
Wafer Fab Site	: FREISING	Wafer Process:	P9722		
Protective Die Coating	: 10KACN				
Qualification: Plan I Test Results					
Reliability Test	Conditions		Sample Size (PASS/FAIL)		
Electrical Char	Approved by Product Engineer	PASS			
ESD (CDM)	1500 V	3/0			
· · · · ·					
Manufacturability	Wafer Fab (per mfg. Site specif	ication)	PASS		
Manufacturability Manufacturability-TQ	Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi	,	PASS		

Qualification Vehicle #6: SN74AUP1G08DCKR					
Wafer Fab Site	: FREISING	Wafer Process:	P9722		
Protective Die Coating	10KACN				
Qualification: Pla	n 🛛 Test Results				
Reliability Test	Conditions	Sample Size (PASS/FAIL)			
Electrical Char	Approved by Product Engineer	PASS			
ESD (CDM)	1500 V		3/0		
Manufacturability	Wafer Fab (per mfg. Site specif	fication)	PASS		
Manufacturability-TQ	Assembly (per mfg. Site specifi		PASS		
	ion tests "pass" on zero fails for				
Q	ualification Vehicle #7: SN74A	UP1G125DCKR	1		
Wafer Fab Site	FREISING	Wafer Process:	P9722		
Protective Die Coating	: 10KACN				
Qualification: 🗌 Pla	n 🛛 Test Results	-	•		
Reliability Test	Conditions		Sample Size (PASS/FAIL)		
Electrical Char	Approved by Product Engineer		PASS		
ESD (CDM)	1500 V		3/0		
Manufacturability	Wafer Fab (per mfg. Site specif	fication)	PASS		
Manufacturability-TQ	Assembly (per mfg. Site specifi	cation)	PASS		
Notes: Qualification tests "pass" on zero fails for each test					
Qualification Vehicle #8: SN74AUP1G126DCKR					
Wafer Fab Site	: FREISING	Wafer Process:	P9722		
Protective Die Coating	: 10KACN				
Qualification: 🗌 Plan 🛛 Test Results					
Reliability Test	Conditions		Sample Size (PASS/FAIL)		
Electrical Char	Approved by Product Engineer		PASS		
ESD (CDM)	1500 V		3/0		
X-Ray	Bottom Side only		5/0		
Manufacturability	Wafer Fab (per mfg. Site specification)		PASS		
Manufacturability-TQ	Assembly (per mfg. Site specification)		PASS		
Notes: Qualification tests "pass" on zero fails for each test					
Qualification Vehicle #9: SN74AUP1G14DCKR					
Wafer Fab Site	: FREISING	Wafer Process:	P9722		
Protective Die Coating	: 10KACN				

Electrical Char A ESD (CDM) 1 Manufacturability V Manufacturability-TQ A Notes: Qualification Qualification: Protective Die Coating: Qualification: Plan Reliability Test C Electrical Char A ESD (CDM) 1 Manufacturability V Manufacturability V Manufacturability-TQ A	Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specif	cation) each test	Sample Size (PASS/FAIL) PASS 3/0 PASS PASS PASS PASS PASS		
ESD (CDM) 1 Manufacturability V Manufacturability-TQ A Notes: Qualification Wafer Fab Site: Vafer Fab Site: Protective Die Coating: Plan Reliability Test C Electrical Char A ESD (CDM) 1 Manufacturability V Manufacturability-TQ A	1500 V Wafer Fab (per mfg. Site specified Assembly (per mfg. Site specified Assembly (per mfg. Site specified In tests "pass" on zero fails for alification Vehicle #10: SN74, FREISING 10KACN IOKACN Onditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specified Assembly (per mfg. Site specified	cation) each test AUP1G17DCKR	3/0 PASS PASS PASS P9722 Sample Size (PASS/FAIL)		
Manufacturability V Manufacturability-TQ A Notes: Qualification Qualification: Protective Die Coating: Qualification: Plan Reliability Test C Electrical Char A ESD (CDM) 1 Manufacturability-TQ A	Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi on tests "pass" on zero fails for alification Vehicle #10: SN74 , FREISING 10KACN Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi	cation) each test AUP1G17DCKR	PASS PASS PASS P9722 Sample Size (PASS/FAIL)		
Manufacturability-TQ A Notes: Qualification Qualification: Qualification: Protective Die Coating: Plan Reliability Test C Electrical Char A ESD (CDM) 1 Manufacturability-TQ A	Assembly (per mfg. Site specifi on tests "pass" on zero fails for alification Vehicle #10: SN74 , FREISING 10KACN Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi	cation) each test AUP1G17DCKR	PASS P9722 Sample Size (PASS/FAIL)		
Notes: Qualification Wafer Fab Site: Wafer Fab Site: Protective Die Coating: Protective Die Coating: Qualification: Plan Reliability Test C Electrical Char A ESD (CDM) 1 Manufacturability-TQ A	on tests "pass" on zero fails for alification Vehicle #10: SN74, FREISING 10KACN Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi	each test AUP1G17DCKR	P9722 Sample Size (PASS/FAIL)		
Notes: Qualification: Protective Die Coating: Qualification: Plateria Reliability Test A Electrical Char A ESD (CDM) 1 Manufacturability-TQ A	on tests "pass" on zero fails for alification Vehicle #10: SN74, FREISING 10KACN Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi	each test AUP1G17DCKR	Sample Size (PASS/FAIL)		
Wafer Fab Site: Protective Die Coating: Qualification: Plan Reliability Test C Electrical Char A ESD (CDM) 1 Manufacturability-TQ A	FREISING 10KACN Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi		Sample Size (PASS/FAIL)		
Protective Die Coating:Qualification:PlanReliability TestCElectrical CharAESD (CDM)1ManufacturabilityVManufacturability-TQA	10KACN Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi	Wafer Process:	Sample Size (PASS/FAIL)		
Qualification:PlanReliability TestCElectrical CharAESD (CDM)1ManufacturabilityVManufacturability-TQA	Test Results Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specifi Assembly (per mfg. Site specifi		(PASS/FAIL)		
Reliability TestCElectrical CharAESD (CDM)1ManufacturabilityVManufacturability-TQA	Conditions Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specif Assembly (per mfg. Site specifi		(PASS/FAIL)		
Electrical CharAESD (CDM)1ManufacturabilityVManufacturability-TQA	Approved by Product Engineer 1500 V Wafer Fab (per mfg. Site specif Assembly (per mfg. Site specifi		(PASS/FAIL)		
ESD (CDM) 1 Manufacturability V Manufacturability-TQ A	1500 V Wafer Fab (per mfg. Site specif Assembly (per mfg. Site specifi		DVCC		
ManufacturabilityVManufacturability-TQA	Wafer Fab (per mfg. Site specif Assembly (per mfg. Site specifi		rass		
Manufacturability-TQ A	Assembly (per mfg. Site specifi		3/0		
		fication)	PASS		
Notes: Qualification	on tests "pass" on zero fails for	Assembly (per mfg. Site specification)			
Quanneation		each test			
Qua	alification Vehicle #11: SN74A	UP1G240DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722		
Protective Die Coating:	: 10KACN				
Qualification: 🗌 Plan 🛛 Test Results					
Reliability Test C	Conditions		Sample Size (PASS/FAIL)		
Electrical Char A	Approved by Product Engineer		PASS		
ESD (CDM) 1	1500 V		3/0		
Manufacturability V	Wafer Fab (per mfg. Site specification)		PASS		
Manufacturability-TQ A	Assembly (per mfg. Site specification)		PASS		
Notes: Qualification tests "pass" on zero fails for each test					
Qualification Vehicle #12: SN74AUP1G32DCKR					
Wafer Fab Site:	FREISING	Wafer Process:	P9722		
Protective Die Coating:	10KACN				
Qualification: Plan I Test Results					
Reliability Test C	Conditions		Sample Size (PASS/FAIL)		
Electrical Char A	Approved by Product Engineer	PASS			
	1500 V		3/0		
· · · · ·	Wafer Fab (per mfg. Site specif	PASS			
-	Assembly (per mfg. Site specifi	,	PASS		
Notes: Qualification tests "pass" on zero fails for each test					

Qualification Vehicle #13: SN74AUP1G34DCKR						
Wafer Fab Site	: FREISING	Wafer Process:	P9722			
Protective Die Coating	: 10KACN					
Qualification: 🗌 Pla	n 🛛 Test Results	I				
Reliability Test	Conditions	Sample Size (PASS/FAIL)				
Electrical Char	Approved by Product Engineer		PASS			
ESD (CDM)	1500 V		3/0			
Manufacturability	Wafer Fab (per mfg. Site speci	fication)	PASS			
Manufacturability-TQ	Assembly (per mfg. Site specif	ication)	PASS			
	ion tests "pass" on zero fails for					
Ç	ualification Vehicle #14: SN74	AUP1G79DCKR	1			
Wafer Fab Site	FREISING Wafer Process:		P9722			
Protective Die Coating	10KACN					
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions	Sample Size (PASS/FAIL)				
Electrical Char	Approved by Product Engineer	PASS				
ESD (CDM)	1500 V		3/0			
Manufacturability	Wafer Fab (per mfg. Site specification)		PASS			
Manufacturability-TQ	Assembly (per mfg. Site specification)		PASS			
Notes: Qualification tests "pass" on zero fails for each test						
Qualification Vehicle #15: SN74AUP1G80DCKR						
Wafer Fab Site	: FREISING	Wafer Process:	P9722			
Protective Die Coating	: 10KACN					
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions		Sample Size (PASS/FAIL)			
Electrical Char	Approved by Product Engineer	PASS				
ESD (CDM)	1500 V	3/0				
Manufacturability	Wafer Fab (per mfg. Site specification)		PASS			
Manufacturability-TQ	Assembly (per mfg. Site specif	PASS				
Notes: Qualificat	ion tests "pass" on zero fails for	each test				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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